

Used XRD Equipment for Sale

Philips 1450 XRD PDP-11/03 Computer

Rigaku D/Max-IIV

Automatic Vertical XRD System

VR-11 X23-LS11/23 Computer

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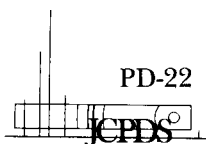
For further information contact:

JCPDS

International Centre for Diffraction Data

1601 Park Lane, Swarthmore, PA 19081

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PD-22

JCPDS

Powder Diffraction File 33-34

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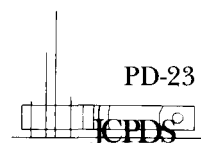
For further information contact:

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International Centre for Diffraction Data

1601 Park Lane, Swarthmore, PA 19081

USA (215) 328-9400 Telex: 847170



PD-23

JCPDS

Applications Invited

for

Assistant to the Editor-in-Chief

(Powder Diffraction File)

The JCPDS - International Centre for Diffraction Data, is inviting applications for an Assistant to the Editor-in-Chief. The major function of the Editor-in-Chief is to scrutinize and evaluate, with the help of editorial consultants, all data submitted to the Powder Diffraction File. Because of the expanded work load over the past several years, due to the processing of increasing numbers of patterns and the improvement in quality of data, the International Centre has decided to supplement the in-house editorial effort by providing an assistant to understudy the existing Editor-in-Chief.

Applicants should have practical experience in the recording and processing of X-ray powder diffraction data, should be able to interface with other editors, and should have some literacy in computer programming.

The JCPDS - International Centre for Diffraction Data has achieved a world-wide reputation for excellence and has been providing high quality powder diffraction data bases for almost 50 years. This career position offers the chance to interface with internationally acclaimed experts in the Powder Diffraction field and to provide a valuable service to the scientific community. The International Centre offers a competitive salary and a comprehensive benefits package.

Anyone interested in learning more about this position should forward a detailed summary of their professional experience to:

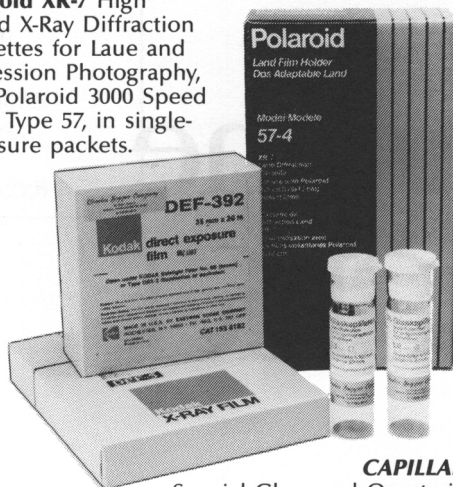
Mr. Julian Messick, General Manager
JCPDS-ICDD
1601 Park Lane
Swarthmore, PA 19081-2389 U.S.A.

PD-21

Capillary Tubes and Laboratory Supplies for X-Ray Diffraction Use

Kodak Direct Exposure Film especially developed for X-ray diffraction analysis. Available in 35mm x 20m rolls and in 50 sheet boxes.

Polaroid XR-7 High Speed X-Ray Diffraction Cassettes for Laue and Precession Photography, and Polaroid 3000 Speed Film, Type 57, in single-exposure packets.



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PD-24

Advance Your PDF Skills

Attend a JCPDS-ICDD Short Course and Workshop

A series of 3 day courses is being offered by JCPDS-ICDD in the methods of identification and characterization of crystalline substances through the use of powder diffraction data.

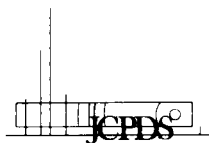
The purpose of these courses is to build proficiency of the user in the interpretation of experimental powder data, especially in the application of information provided in the *Powder Diffraction File*.

Hands on work sessions. Use of both manual and computer/search methods. Descriptive workbook with illustrative examples.

November 14-16, 1989 San Jose, CA Hotel Le Baron
February 6-8, 1990 Denver, CO
April 17-19, 1990 Florida

For further information contact:

Ms. Josephine Felizzi
JCPDS-ICDD
1601 Park Lane, Swarthmore, PA 19081
USA (215) 328-9400 Telex: 847170



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EISI Elemental and Interplanar Spacing Index

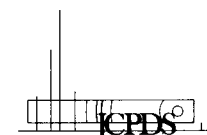
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data ...

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using combinations
of Elemental Data
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and then ...

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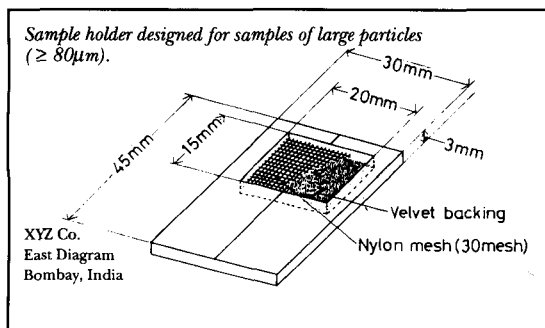
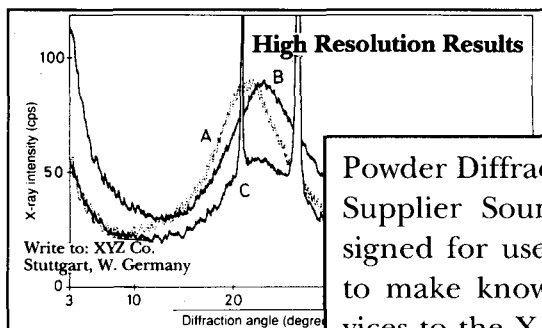
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Advertising Announcements

Supplier Source Directory

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 Professor of Chemistry and Geology
 The Eastern University
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 Telephone
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 Consulting Services in XRD: Mineralogy



High Temperature

Tc(K)	Compound
551	$\text{Ba}_{0.8}\text{Sr}_{1.2}\text{NaNb}_5\text{O}_{15}$
—	$\text{BaSrKNb}_5\text{O}_{15}$
547	$\text{BaSrNa}_{0.5}\text{K}_{0.5}\text{Nb}_5\text{O}_{15}$
150	$\text{BaSrNaNb}_5\text{O}_{15}$
225	$\text{Ba}_2\text{LiTa}_5\text{O}_{15}$
428	$\text{Ba}_2\text{NaNb}_{1.25}\text{Ta}_{3.75}\text{O}_{15}$

Write to:
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Powder Diffraction announces the Supplier Source Directory – designed for use by those who wish to make known their special services to the X-ray diffraction community. Rates are modest (no discounts for agencies), beginning at \$125.00 for one insertion (business card size).

For details please write or call Mary M. Rossi, Advertising Manager, JCPDS-ICDD at Swarthmore. (215-328-9403).

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Write to Receive Information
 Name/Title _____
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 City _____ State _____
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XRD Company
 Roentgen, Pennsylvania
 Telephone

X-ray Diffraction Software for Personal Computers

XYZ Software Inc.
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announces the availability of the following software:

System 1:	Forensics	PC
System 2:	CD-ROM	PC

Examples of possible insertions are indicated on the Directory shown here (80% of actual size.)

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Charles Supper Corporation	XIX	PD-24	Materials Data	VII	PD-7
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inel Inc. (Formerly American Instruments)	X	PD-11	Scintag	V	PD-5
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Kayabacho Nihonbashi Chuo-ku, Tokyo 103, Japan for subscriptions for Japan, China,
Taiwan, Malaysia, the Philippines, Indonesia and Korea.

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X-ray...
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Rigaku's Thin Film Diffractometer Attachment

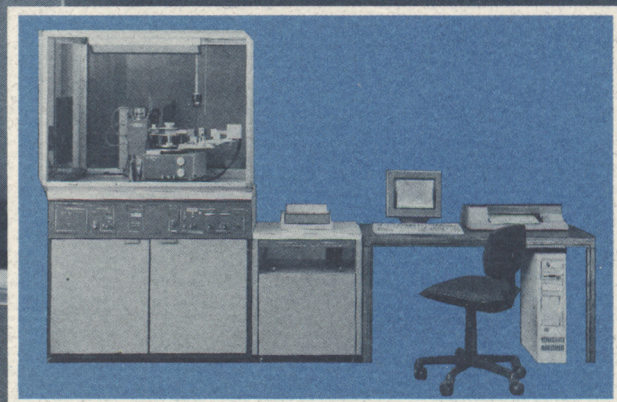
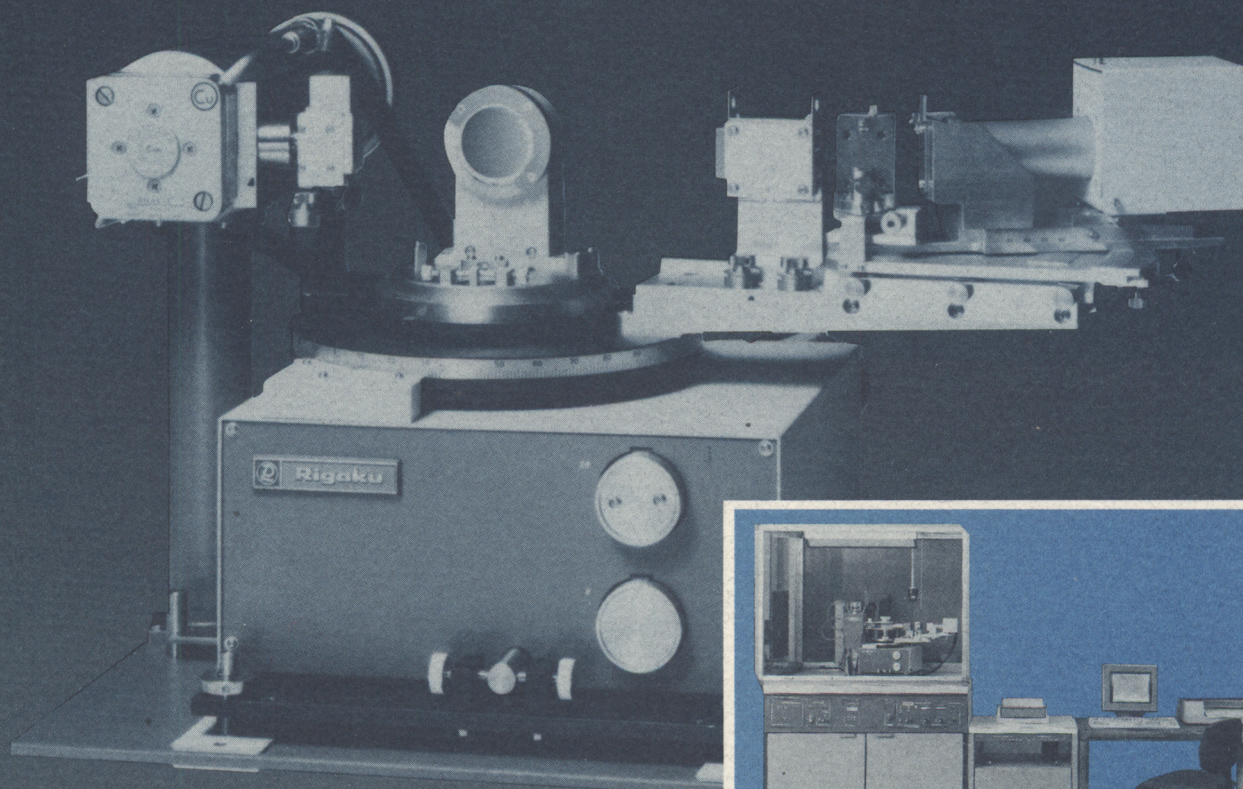
...Throwing light
on 100Å film.

X-ray diffractometry of thin films, which has so far been exceedingly difficult, is now possible with Rigaku's Thin Film Attachment.

Up to now, obtaining a sharp X-ray diffraction profile of a thin film has been a problem; the extremely thin sample weakens the intensity of the diffracted rays, resulting in relatively low signals and high backgrounds. Moreover, since the conventional diffractometer is designed for a θ - 2θ coupled scan, intense diffracted rays from the substrate material overwhelm the diffracted rays from the thin film sample, making it difficult to obtain reliable data.

The dilemma has now been solved by newly developed optics from Rigaku (pat. pend.). Used in conjunction with our wide angle diffractometer, the Thin Film Attachment employs a low-angle incidence method with parallel beam optics that increase the diffraction intensities of thin film samples. A scan system for 2θ alone and an intraplane sample rotation mechanism enhance efficiency. Rigaku has thus made thin film measurement feasible with only the X-ray flux available from a conventional sealed-off X-ray tube.

Throwing light on 100Å... only Rigaku has the technology to make it happen!



D/Max-B Wide Angle Diffraction System with IBM System/2

Rigaku

Rigaku / USA, Inc. • Northwoods Business Park • Suite #190
200 Rosewood Drive • Danvers, MA 01923 • (508) 777-2446

PD-27

Published online by Cambridge University Press

From now on all other powder diffractometers will be measured against this one.



It's the new Philips PW1800.

It's the most advanced system of its type available anywhere. It's also the most versatile and the easiest to operate.

It's designed for easy, automatic measurement of a wide range of sample types in a variety of forms and quantities including powders, clays, pastes and filters. Built-in electronics control and supervise all diffractometry functions to assure reliability. What's more, the PW1800 actually monitors itself to see that it is functioning properly. And alerts the operator if it senses trouble ahead. In fact, everything about this new system has been engineered to simplify operation.

Even its appearance underscores its uniqueness. It's totally enclosed, totally integrated to assure complete radiation and contamination protection. Which means it can be installed safely and quickly in the laboratory or on the production line.

And among the things you don't see in this unique system is the newly developed, permanently-aligned goniometer that combines ease of operation with high precision and outstanding analytical performance. Built-in robotics for sample handling. And a new, highly-efficient generator that not only requires less space, but actually reduces power consumption as well.

It's the new Philips PW1800. It's the new standard of the industry. And it's backed by the worldwide support resources of the Philips organization.

For complete details, contact:

Philips Electronic Instruments, Analytical X-Ray Group,
85 McKee Drive, Mahwah, NJ 07430, Tel. (201) 529-3800.

(Outside U.S.A.) Philips Scientific & Analytical Equipment,
Industrial & Electro-acoustic Systems, Lelyweg 1,
7602 EA Almelo, The Netherlands. Tel (31) 5490-39911.



PHILIPS

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